

Notice of References Cited		Application/Control No. 10/595,742	Applicant(s)/Patent Under Reexamination SUNAGA ET AL.	
		Examiner LY D. PHAM	Art Unit 2827	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0187721 A1	08-2006	Freebern, Margaret	365/193
*	B	US-6,809,946 B2	10-2004	Fujisawa et al.	365/51
*	C	US-6,597,626 B2	07-2003	Hirabayashi, Osamu	365/233.1
*	D	US-6,404,695 B1	06-2002	Fujino et al.	365/230.03
*	E	US-6,351,419 B1	02-2002	Dietrich et al.	365/189.04
*	F	US-6,147,919 A	11-2000	Kawabata et al.	365/208
*	G	US-6,026,034 A	02-2000	Suzuki et al.	365/190
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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	X				

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